Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/643,370	DROPPO ET AL.
Examiner	Art Unit

2626

Brian L. Albertalli

SEARCHED					
Class	Subclass	Date	Examiner		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST Search (US-PGPUB, USPAT, USOCR, EPO, JPO, DERWENT, IBM_TDB) - See Search History Printout	4/26/2007	ВА	
IEEE Search - Search Terms: SNR, signal to noise ratio, taylor, random variable, probabalistic	4/26/2007	ВА	
INSPEC Search - Search Terms: SNR, signal to noise ratio, taylor, random variable, probabalistic	4/26/2007	ВА	
ACM Search - Search Terms: SNR, signal to noise ratio, taylor, random variable, probabalistic	4/26/2007	ВА	
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